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Top Images, left to right

(Top) Colorized generation of the second sec

- ELNEs or individual atoms in graphene, Different states or atomic coordination are illustrated at top, LLNEs or carbon K (1s) spectra shown on bottom, Creen, blue and red spectra correspond to the normal sp2 carbon atom, a double-coordinated atoms and a single coordinated tom, respectived using a catana CHLNEs or carbon K (1s) spectra shown on bottom, Creen, blue and red spectra correspond to the normal sp2 carbon atom, a double-coordinated atoms and a single coordinated tom, respectived using a catana CHLNEs or carbon K (1s) spectra shown on bottom, Creen, blue and Mc Koshino (AST, Tsukuba, Japan). Figure 1 from: K. Suenaga et al. "Atom-by-Atom spectroscopy analysis at graphene edge"; Nature 468, 1088 (2010), Permission to use Figure 1 granted by K. Suenaga and Nature Publishing Group. Copyright © 2010, rights managed by Nature Publishing Group. Unfiltered, conventional TEK limage and elemental maps of a capillary blood vessel captured using a Catana (Te Quantum*ER New New re extracted from an FTEFLM-SI dataset acquired using a GTe Quantum*ER Suewith and New Publishing Group. Unfiltered, carbon in the P elemental maps, Sample courtesy of Dr, Wenlang Lin, Mayo Clinic. Color composite EELS composition map from data acquired using a GTe Quantum*ERS system on a 300 kV probe corrected STEM with 1.0 nA beam current. The EELS data was acquired at 4.1 ms/pixel with a 20 mR convergence angle and 4.2 mR collection angle. The 200 x 200 pixel map took under 3 minutes to acquire (164 s). The black areas are Si, which has been omitted for darity. TEM facilities courtesy FLMI and TU Graz, Austria.
- Bottom Images, left to right: (Left) Colorized elemental map based on Pt M-edge (red), Fe L-edge (green), and O K-edge (blue) intensities. Data captured using a Gatan GIF Quantum®ERS and 300 kV probe corrected STEM with 180 pA beam and 5 ms exposure
- (Right) Extracted Pt M_{ise} edges (upper) and Feb ₁₂ edges (lower) from the fit in outer shell (green), bit denotes back uppared using a solar of the outer shell with the per contract of Pt and and an outer shell (green). Depitte the sub-mm proximity of the outer shell to the core, no Pt is detected. The Fe-L2/L3 ratio and peak position vary significantly with the Fe chemistry of the layer. Sample and TEM facilities courtesy McMaster University, Canada. Colorized 14 x 14 elemental map of LaMnO_1 / SrMnO_3 uper lattices grown on SrTiO_(Mn) Red, La-green, The L9L2/L3 ratio and peak position vary significantly with the Fe chemistry of the layer. Sample and TEM facilities courtesy McMaster University, Canada. Colorized 14 x 14 elemental map of LaMnO_1 / SrMnO_3 uper lattices grown on SrTiO_(Mn) Red, La-green, The L9L2/L3 ta was acquired on an Enfinium" (UHV special) coupled to a 100 kV NION UltraSTEM, Image courtesy Mundy, Adamo, Schlom & Muller, Cornell University. (Results published in Monkman & Adamo, et al, Nature Materials, vol 11, 2012).



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(Top left) Dave Tuggle and FEI founder Lyn Swanson working on an early edition FIB column. (Bottom left) A two-lens Schottky column. (Right) Helios NanoLab 660.

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